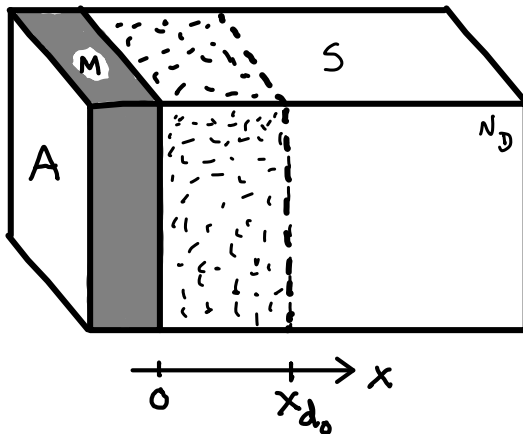
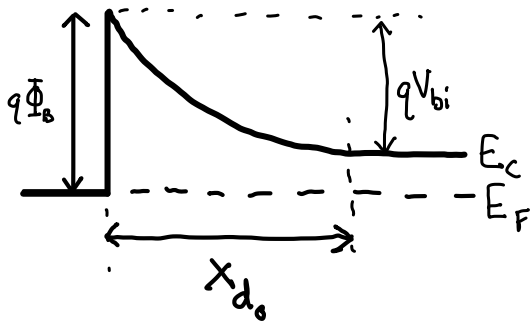
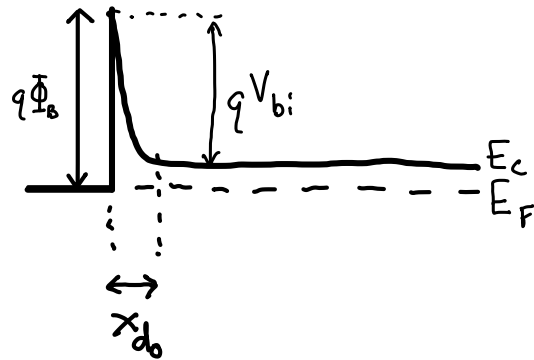


Metal - Semiconductor Junctions

Small N_D (Schottky):

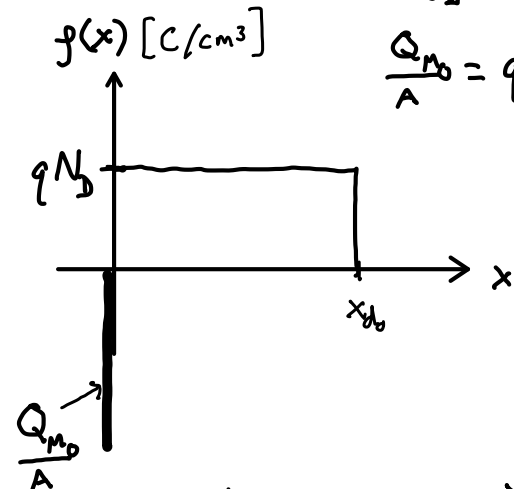


Large N_D (ohmic):

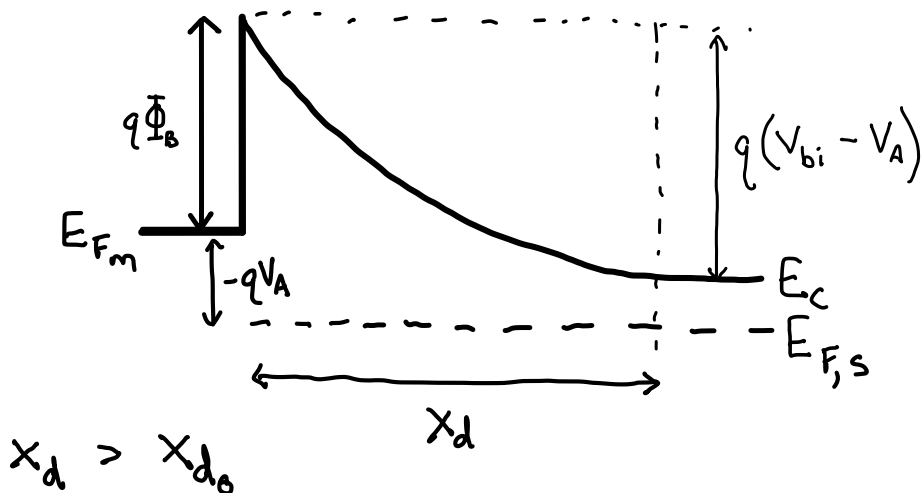


$[Q_{M0}] = \text{coulombs}$

$$\frac{Q_{M0}}{A} = qN_D x_{d0}$$

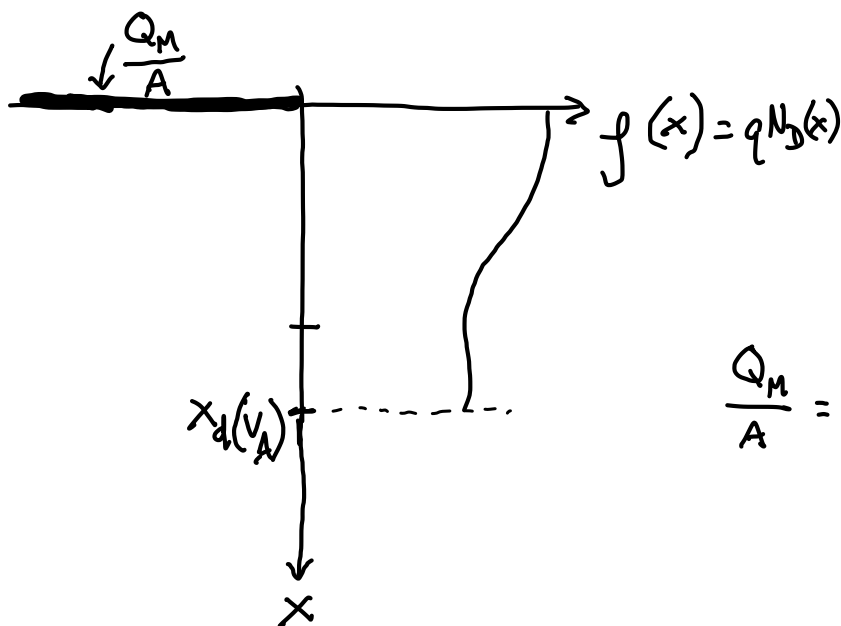
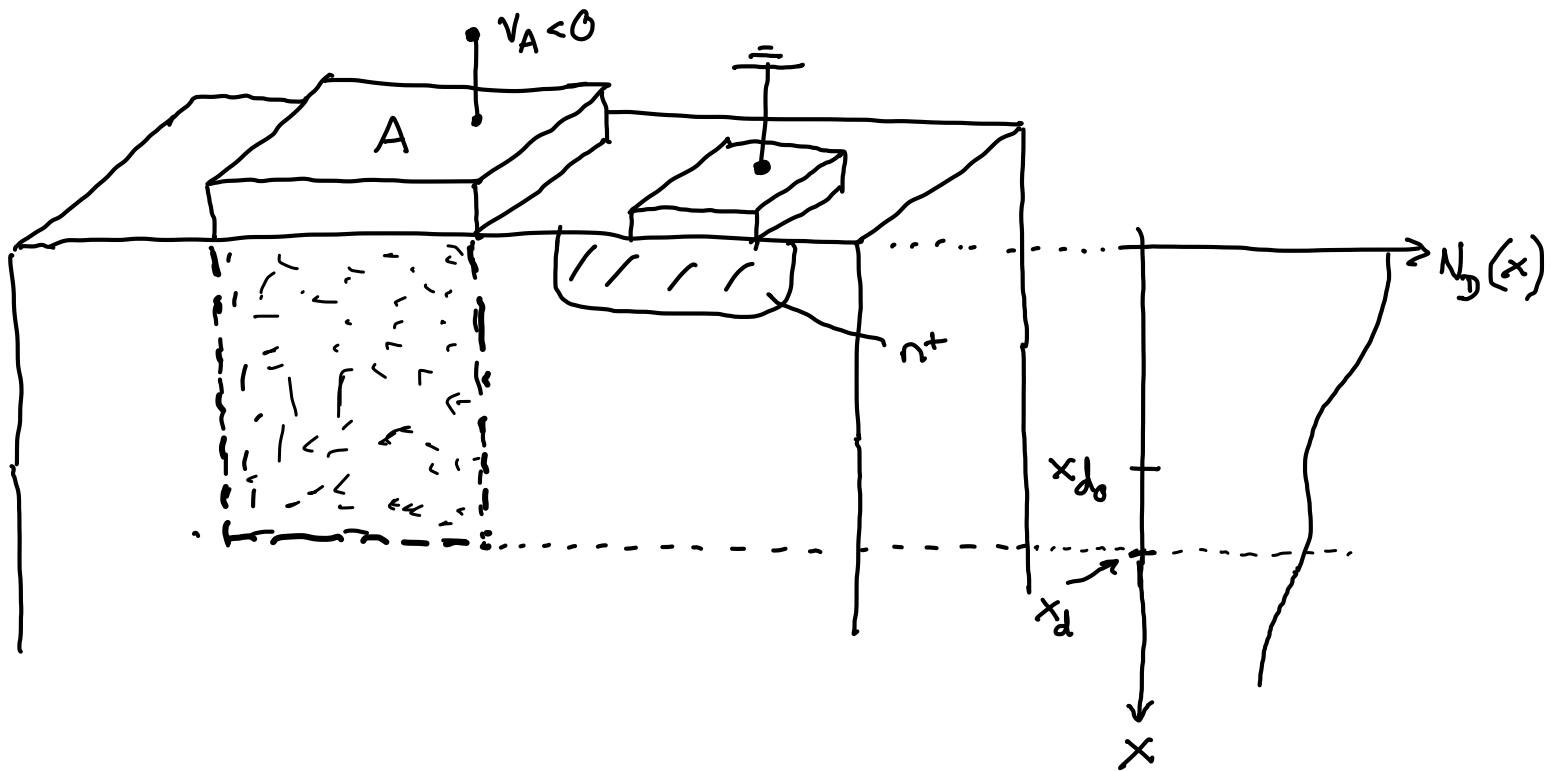


Schottky contact under reverse bias ($V_A < 0$):



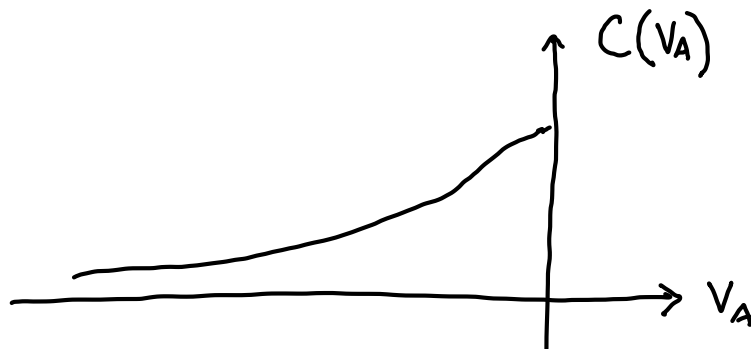
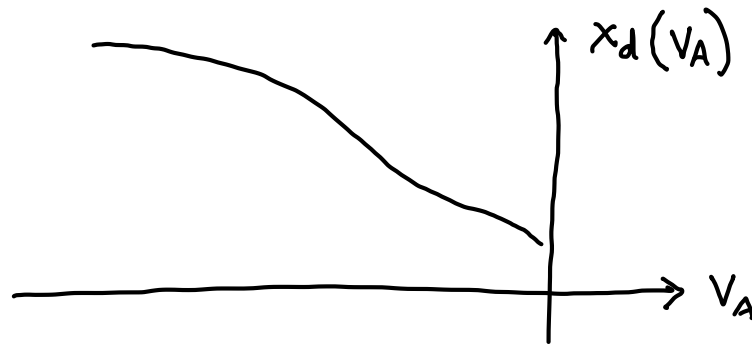
Use of Schottky contact to characterize doping density in moderately doped semiconductor:

- Consider arbitrary doping profile in (vertical) x -direction:



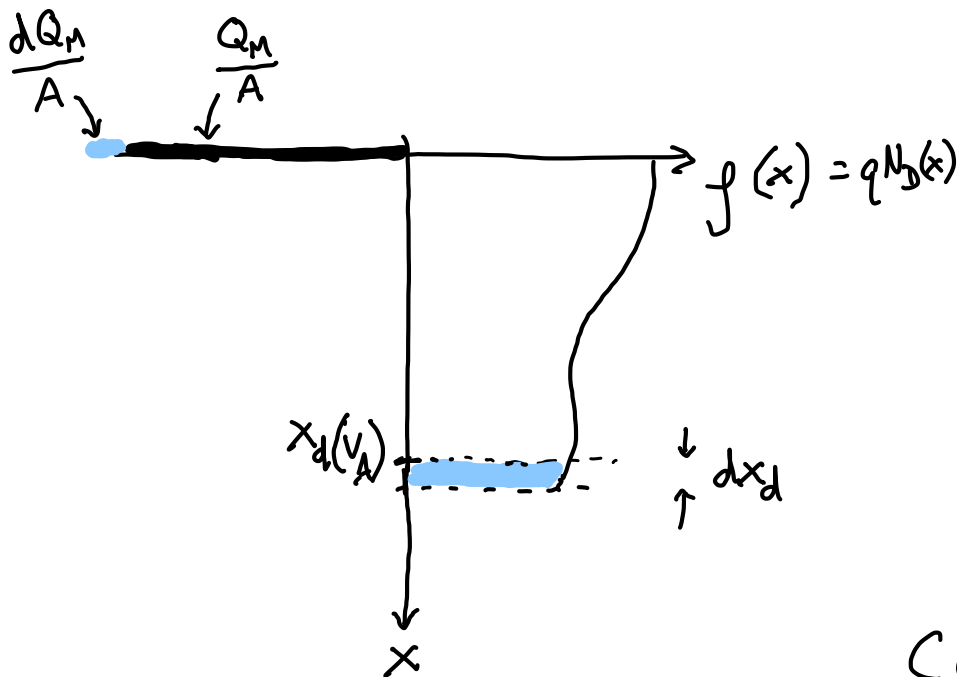
$$\frac{Q_M}{A} = \int_0^{x_d} f(x) dx$$

Apply DC bias V_A to contact and measure C :



$$C(V_A) = \frac{\epsilon_s A}{x_d(V_A)} \quad (1)$$

If $|V_A|$ is increased by $|dV_A|$:



$$\begin{aligned} \frac{dQ_M}{A} &= p(x_d) \cdot dx_d \quad (3) \\ &= qN_D(x_d) \cdot dx_d \end{aligned}$$

$$C(V_A) = -\frac{dQ_M}{dV_A} \quad (2)$$

$$C(V_A) = \frac{\epsilon_s A}{x_d(V_A)} \quad (1)$$

$$C(V_A) = -\frac{dQ_M}{dV_A} \quad (2)$$

$$\frac{dQ_M}{A} = f(x_d) \cdot dx_d = q N_D(x_d) \cdot dx_d \quad (3)$$

From (1):

$$\frac{1}{[C(V_A)]^2} = \frac{x_d^2}{\epsilon_s^2 A^2}$$

$$\frac{d}{dV_A} \left[\frac{1}{C^2} \right] = \frac{2x_d}{\epsilon_s^2 A^2} \cdot \frac{dx_d}{dV_A} \quad (4)$$

From (2) and (3):

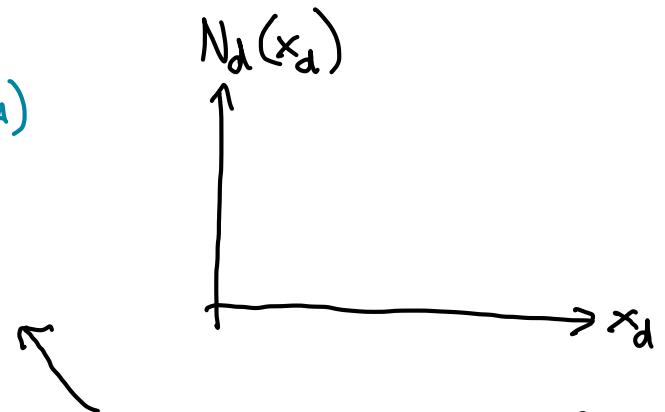
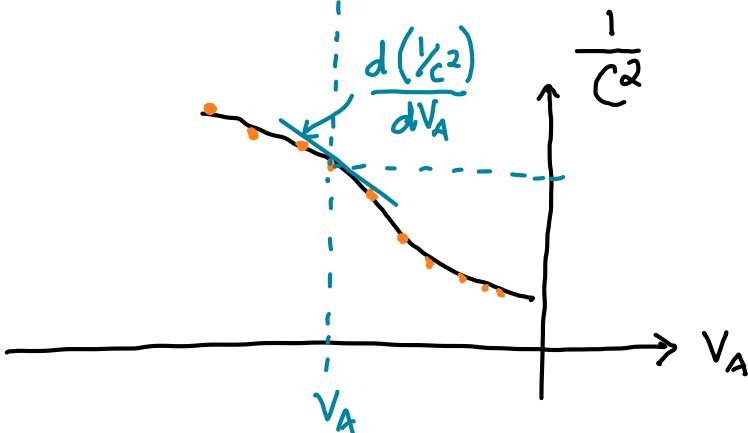
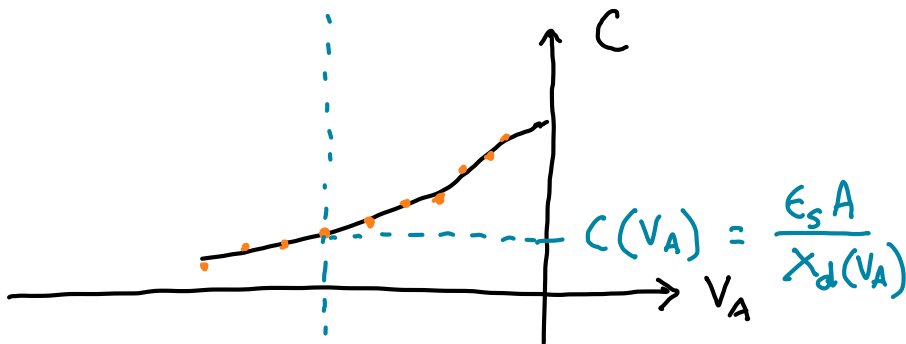
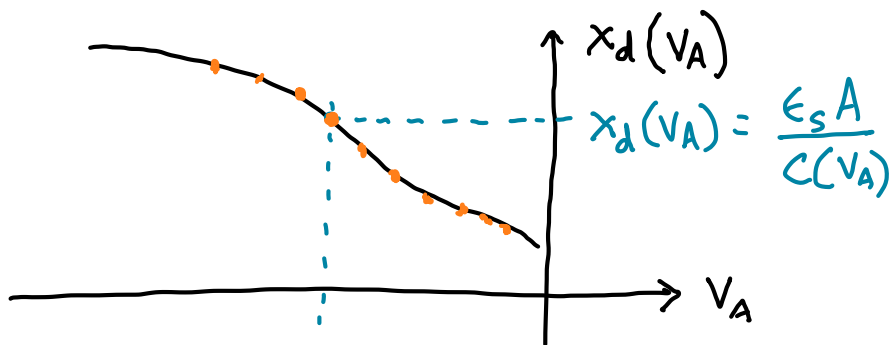
$$C = -\frac{dQ_M}{dV_A} = -\frac{A}{dV_A} \cdot \left(\frac{dQ_M}{A} \right) = -q N_D(x_d) \cdot A \cdot \frac{dx_d}{dV_A} \quad (3)$$

$$\frac{dx_d}{dV_A} = \frac{-C}{q \cdot N_D(x_d) \cdot A} \stackrel{(1)}{=} \frac{-\epsilon_s}{q \cdot N_D(x_d) \cdot x_d} \quad (5)$$

Plug (5) into (4):

$$\frac{d[1/c^2]}{dV_A} = \frac{-2x_d}{\epsilon_s^2 A^2} \cdot \frac{\epsilon_s}{q \cdot N_D(x_d) \cdot x_d}$$

$$N_D(x_d) = \frac{-2}{q \epsilon_s A^2 \left[d(1/c^2)/dV_A \right]}$$



Can use this info to fill in this plot

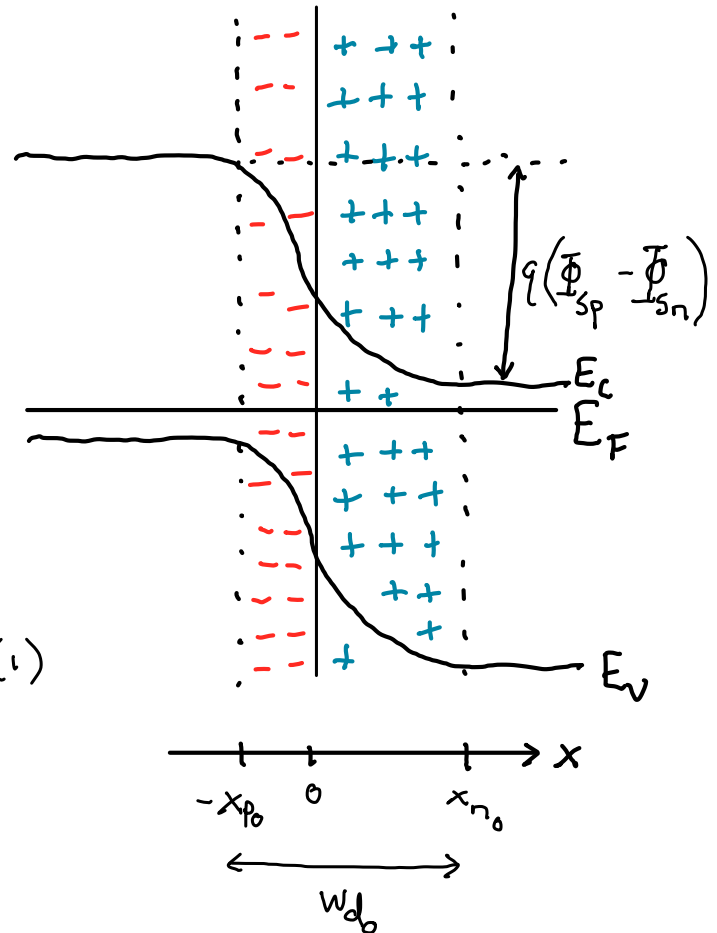
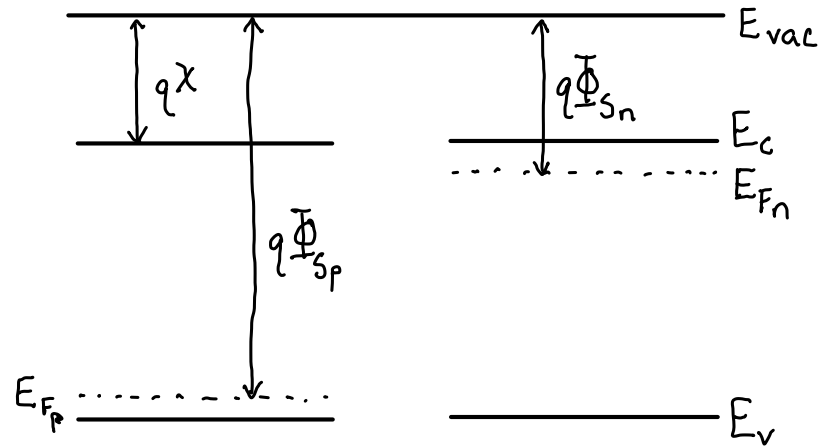
p-n Junctions

p (N_A)

n (N_D)

p (N_A)

n (N_D)



$$A_o = V_{bi} = \Phi_{sp} - \Phi_{sn} = \frac{kT}{q} \ln \left[\frac{N_A N_D}{n_i^2} \right] \quad (1)$$

$$\frac{d\mathcal{E}_x(x)}{dx} = \frac{qN}{\epsilon_s} \quad (2)$$

$$N_A x_{p0} = N_D x_{n0} \quad (3)$$

$$A_o = \frac{1}{2} (x_{n0} + x_{p0}) \mathcal{E}_{max0} \quad (4)$$

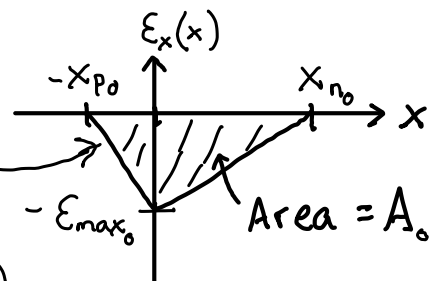
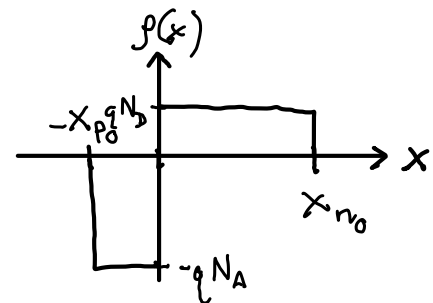
From (1) ~ (4):

$$x_{n0} = \left\{ \frac{2\epsilon_s V_{bi}}{q} \left[\frac{N_A}{N_D(N_A + N_D)} \right] \right\}^{1/2}$$

$$x_{p0} = \left\{ \frac{2\epsilon_s V_{bi}}{q} \left[\frac{N_D}{N_A(N_A + N_D)} \right] \right\}^{1/2}$$

$$w_{d0} = \left[\frac{2\epsilon_s V_{bi}}{q} \left(\frac{1}{N_A} + \frac{1}{N_D} \right) \right]^{1/2} = x_{p0} + x_{n0}$$

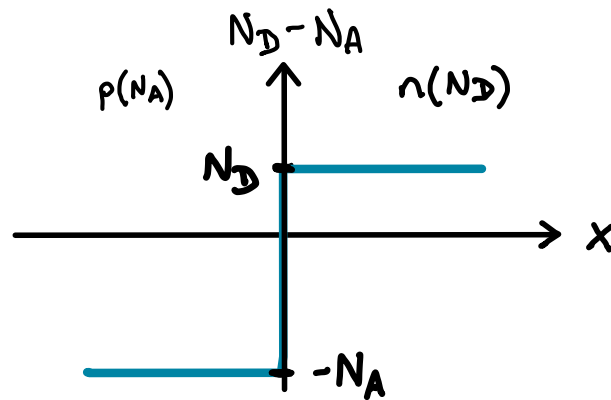
$$\mathcal{E}_{max0} = \frac{2V_{bi}}{w_{d0}}$$



$$\frac{\mathcal{E}_{max0}}{x_{p0}} = \frac{qN_A}{\epsilon_s}$$

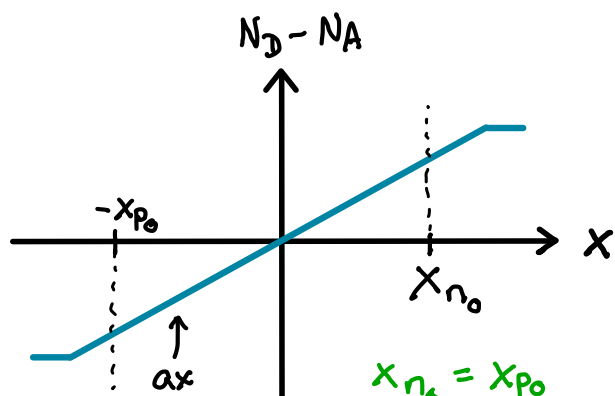
$$\frac{\mathcal{E}_{max0}}{x_{n0}} = \frac{qN_D}{\epsilon_s}$$

1. Abrupt junction (shown on previous page)

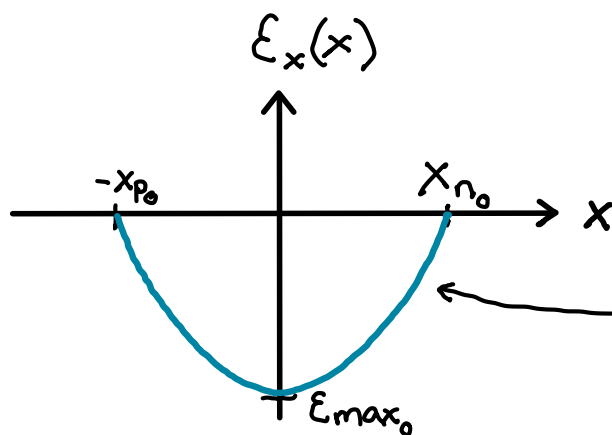
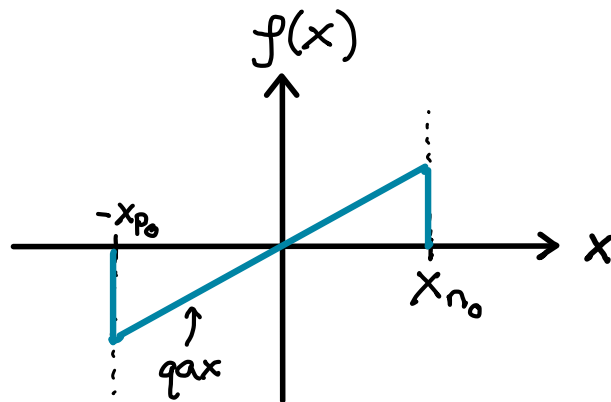


- Formed by epitaxial techniques (e.g., MOCVD, MBE)
- Not all pn junctions are abrupt (e.g., diffused junctions, implanted junctions)
- Analytic solution can be obtained for linearly graded junction (many others can only be solved numerically)

2. Linearly Graded Junction: $N_D - N_A = ax$



$x_{n0} = x_{p0}$
(symmetric junction)

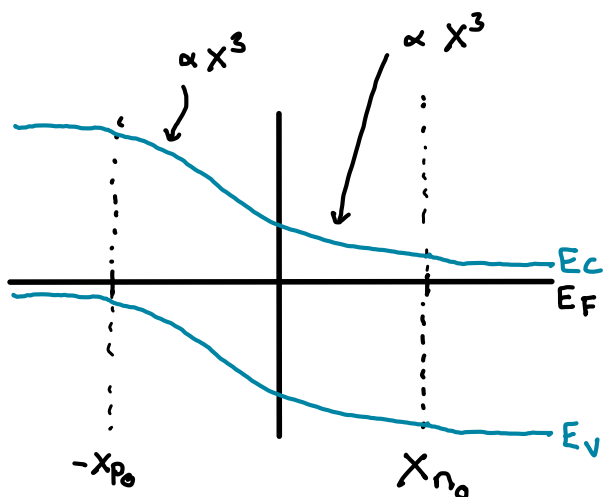


Poisson's equation:

$$\frac{dE_x(x)}{dx} = \frac{\rho(x)}{\epsilon_s} = \frac{qa}{\epsilon_s} x$$

$$E_x(x) = \frac{-qa}{2\epsilon_s} [x_{n0}^2 - x^2]$$

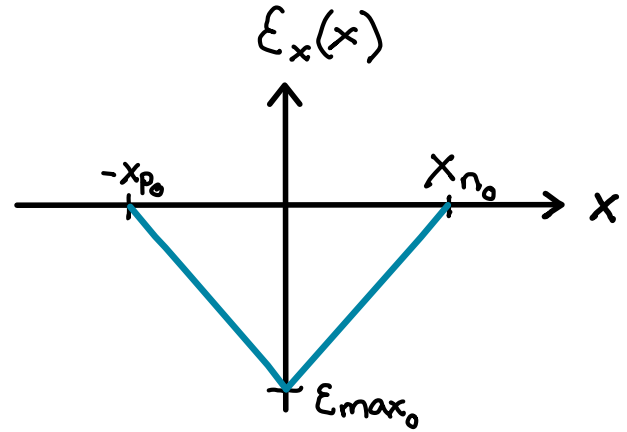
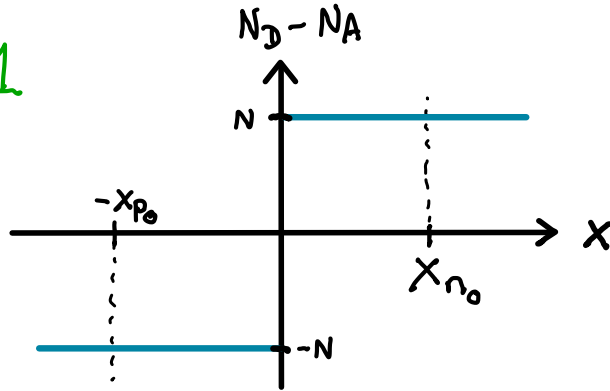
(parabola)



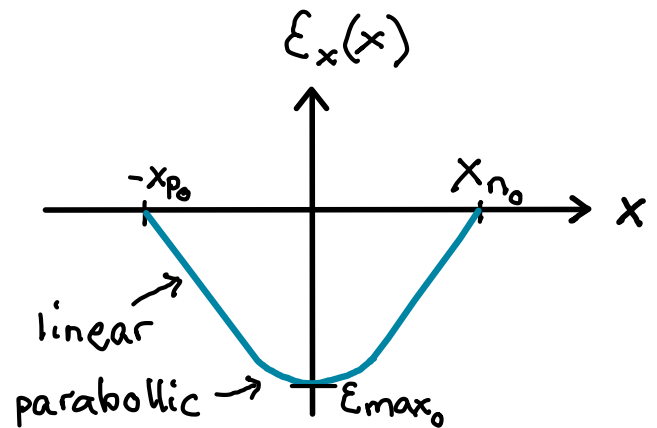
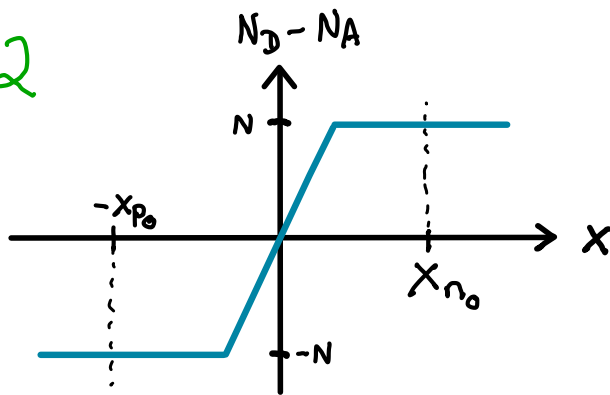
In depletion region,
 $E_x \propto x^2$, so $E_c \propto x^3$
(and $E_v \propto x^3$)

→ Some cases to consider (note: scale for ϵ_x and x is different in each diagram):

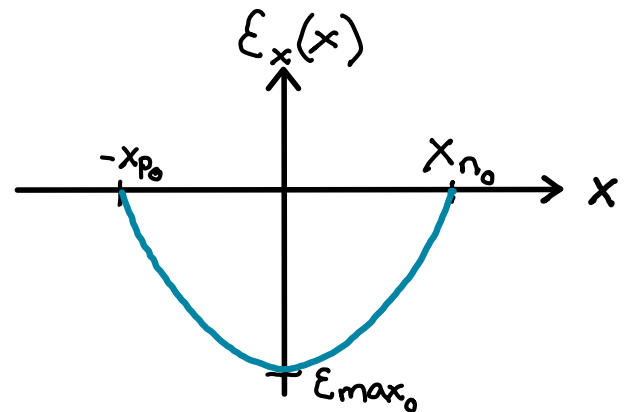
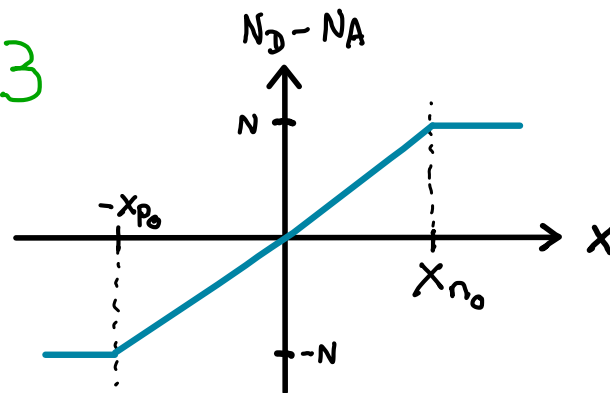
#1



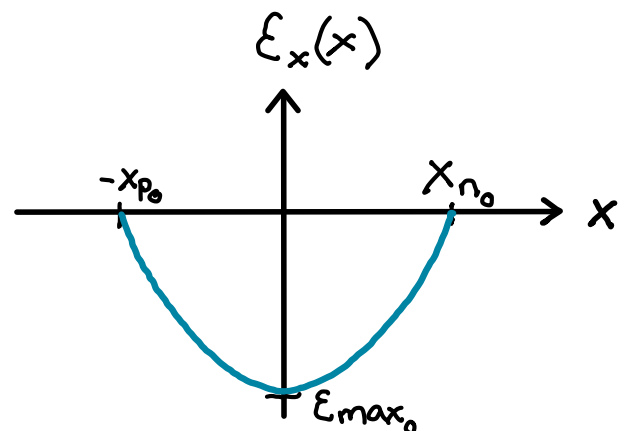
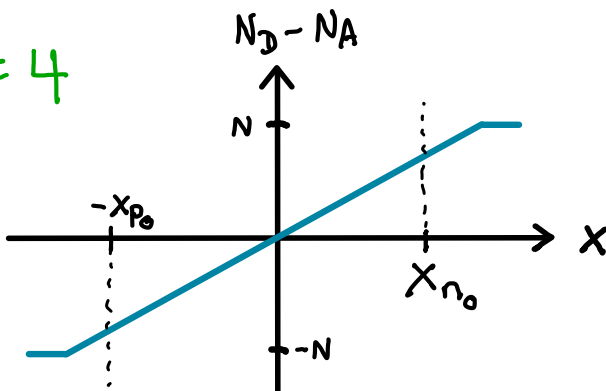
#2



#3

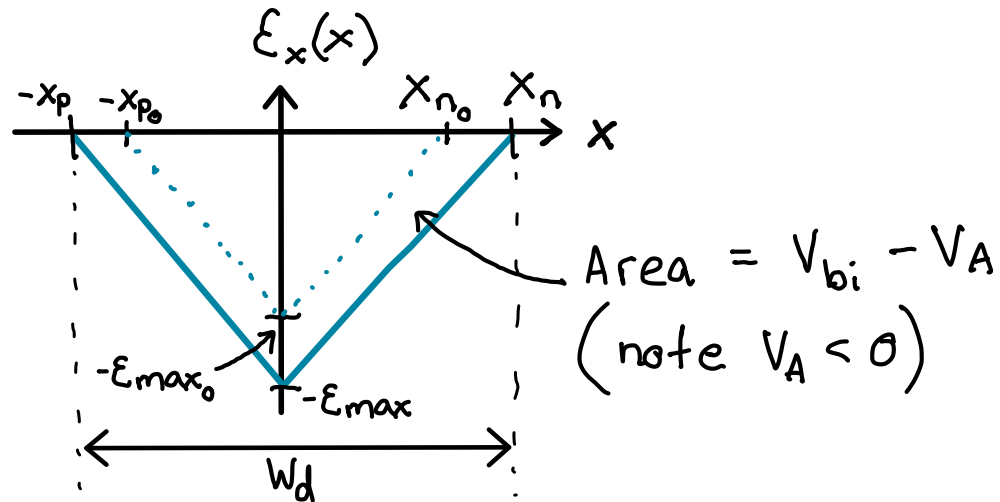


#4



Reverse Biased pn Junctions: E-field

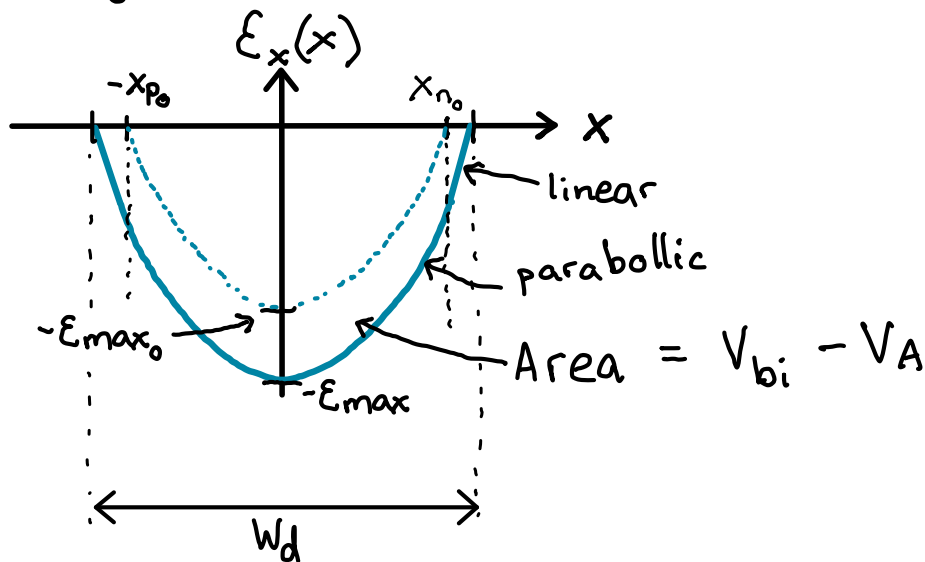
→ Abrupt junction (#1 from last page)



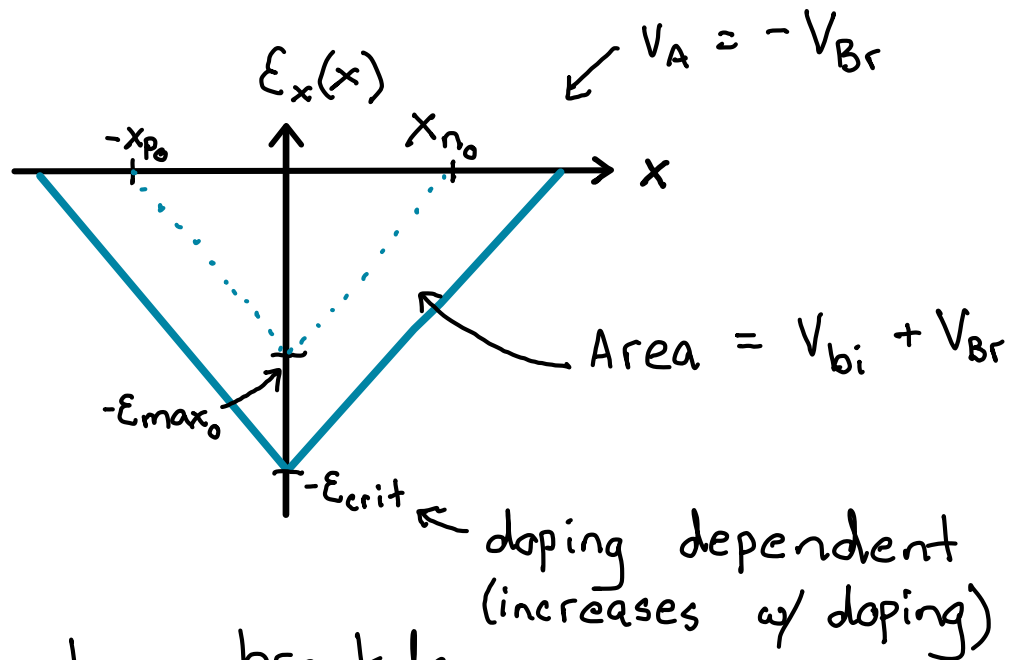
$$W_d = \left[\frac{2\epsilon_s}{q} \left(\frac{1}{N_A} + \frac{1}{N_D} \right) (V_{bi} - V_A) \right]^{1/2}$$

$$E_{max} = \frac{2(V_{bi} - V_A)}{W_d}$$

→ Linear grade in depletion region (#3 from last page):



Breakdown:



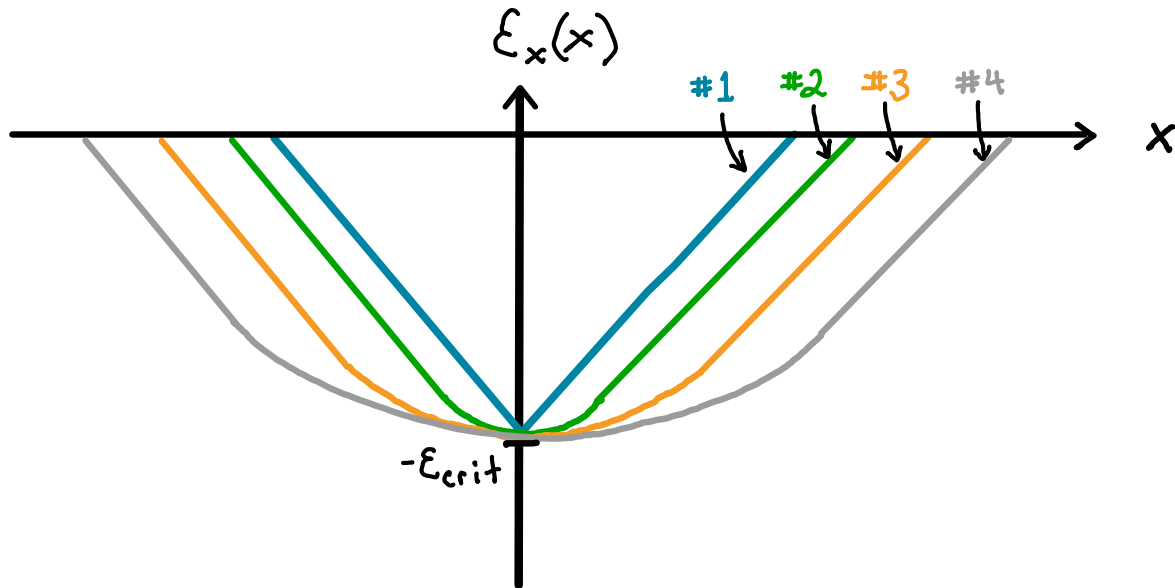
→ Avalanche breakdown

- Multiplication
- Occurs in light to moderately doped structures

→ Zener breakdown

- E -field breaks covalent bonds
- Occurs in heavily doped structures ($\geq 10^{18}$)

Breakdown of structures from p. 9:



• Area under each curve = $V_{bi} + V_{Br}$